Are your X-ray powder diffraction patterns any good?



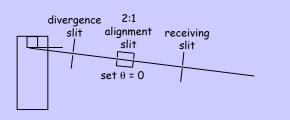
- 1. Is diffractometer properly aligned & operating correctly?
- 2. Is the specimen properly prepared?
- 3. Are proper scan variables used?

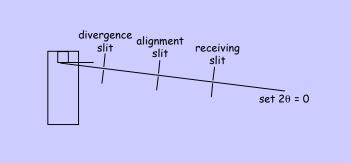
Diffractometer alignment

Alignment steps

Align instrument to see focal spot Set take-off angle

Zero alignment 2:1 alignment





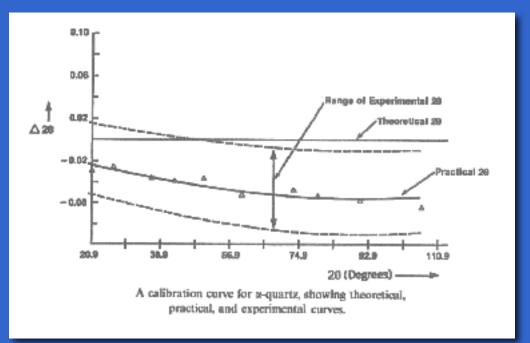
Diffractometer alignment Alignment checks

Run calibration pattern - use suitable standard ex: NIST SRM 640c (Si), others

Compare measured 20 values with NIST or standard values

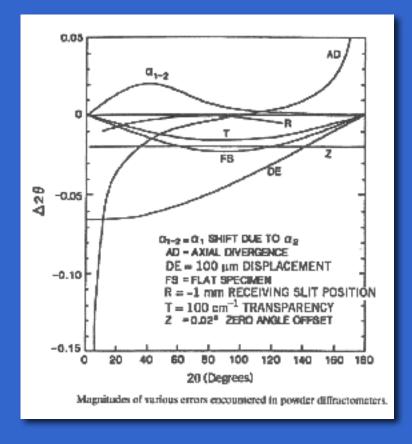
Look for:

intensity loss angle shifts resolution loss



Powder diffractometer

Alignment checks



Diffractometer alignment

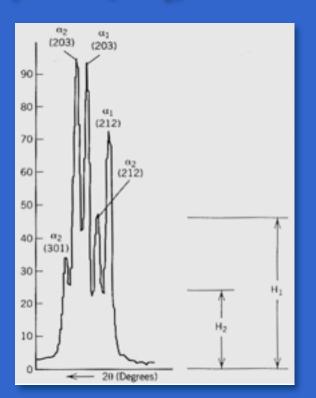
Alignment check

"five fingers of quartz" (SiO₂)

Measure:

position & intensity of (203) α_1

 H_1/H_2



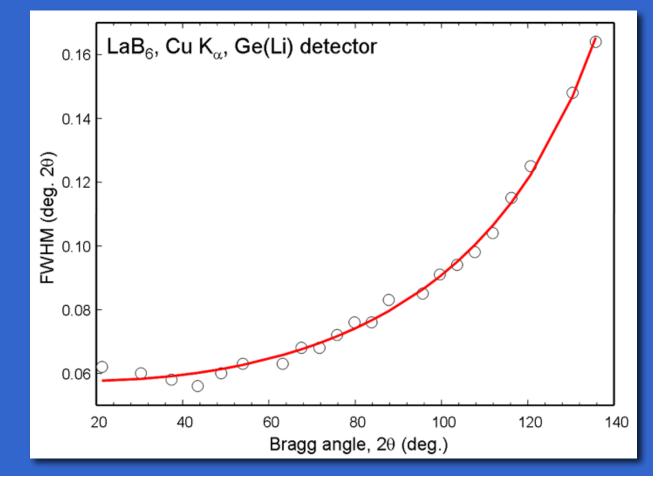
Alignment checks

Run calibration pattern - use suitable standard

Use NIST SRM 660 standard (LaB₆)

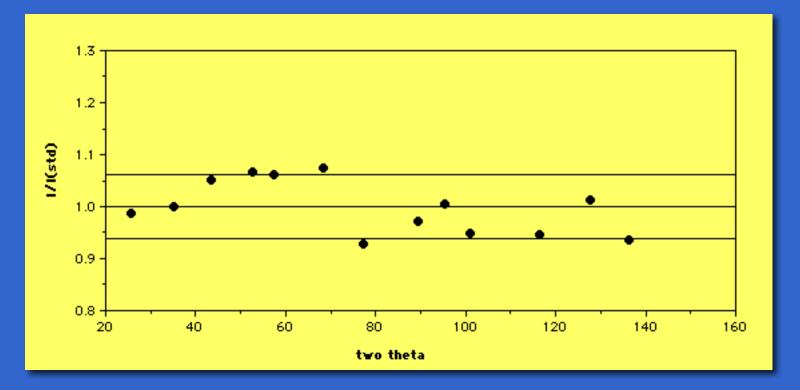
Measure FWHM values

Compare measured FWHM values with NIST values



Alignment checks

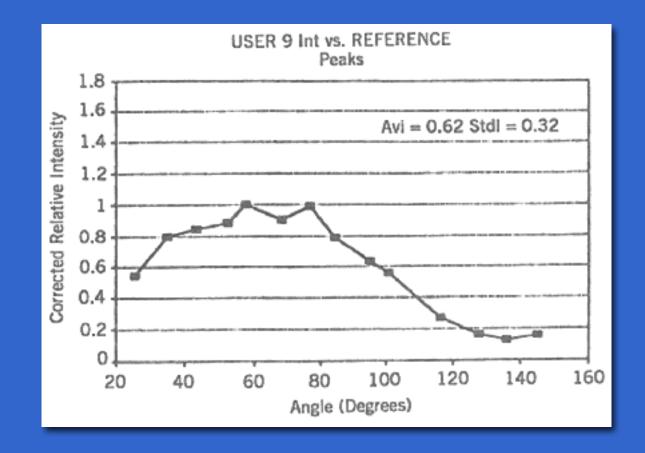
Run calibration pattern - use suitable standard



NIST SRM 1976 (AI_2O_3)

Alignment checks

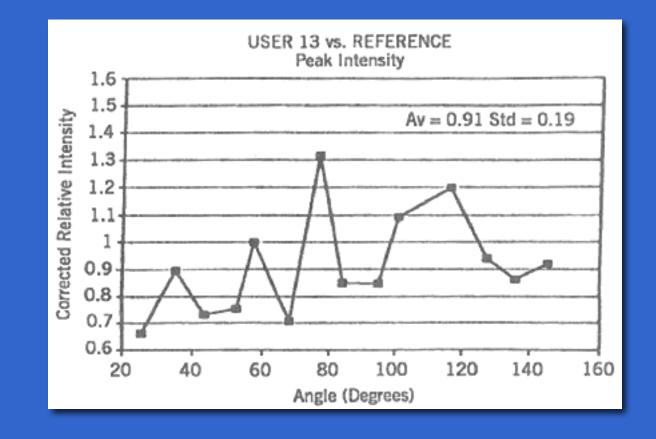
Run calibration pattern - use suitable standard



Powder diffractometer

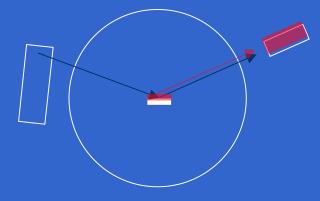
Alignment checks

Run calibration pattern - use suitable standard



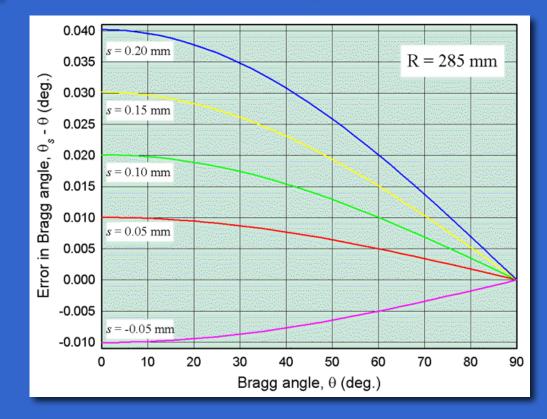
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sample surface must be on diffractometer rotation axis

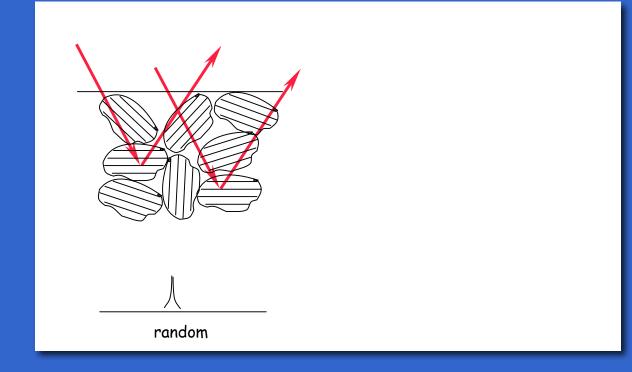


Reflection from off-axis specimen at wrong 2θ angle

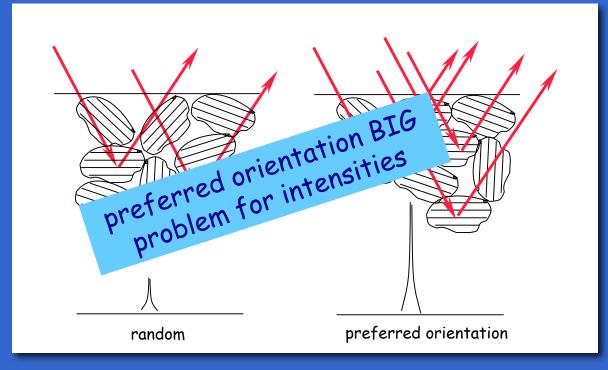
sample surface must be on diffractometer rotation axis



random particle orientation - no "preferred orientation"

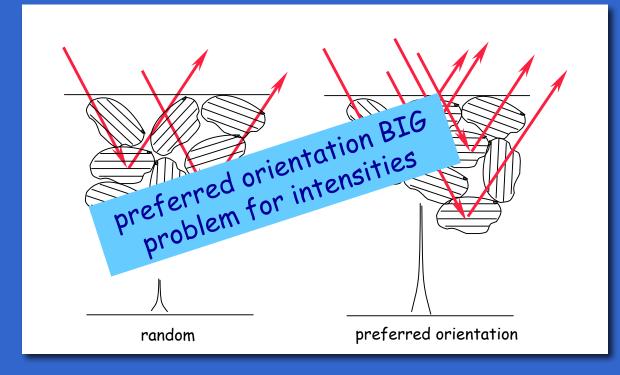


random particle orientation - no "preferred orientation"



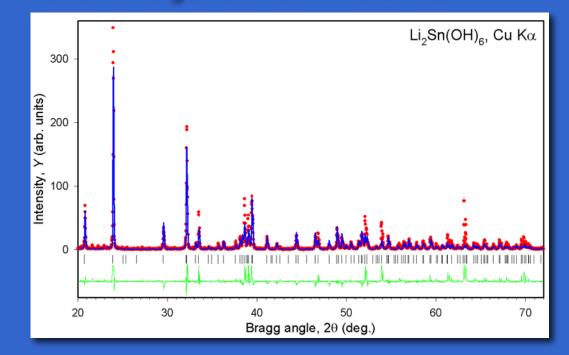
Note: only particles with planes parallel to specimen surface will reflect

random particle orientation - no "preferred orientation"



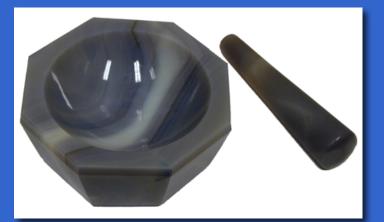
Reflection intensities can be significantly changed

> >10⁶ randomly oriented particles to avoid preferred orientation & to get correct intensities



Measured intensities for coarse powder not correct

Is the specimen properly prepared?

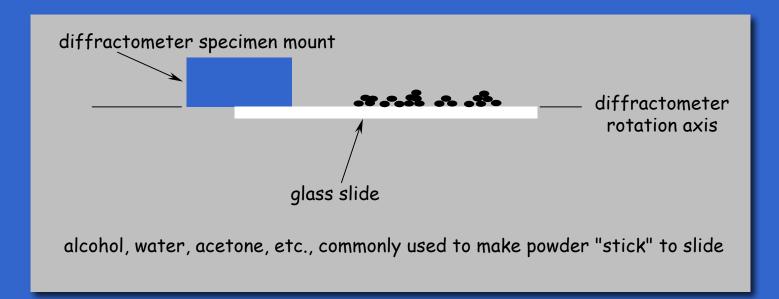


1-10 microns particle size preferred Common techniques - powders

Slide prep Cavity front fill Cavity back fill Cavity side drift

Common prep techniques - powders

Slide prep

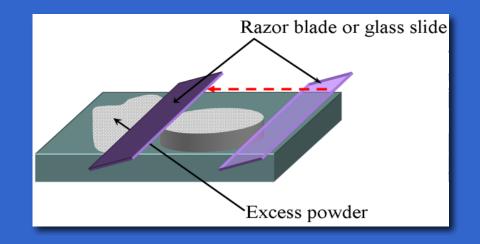


Problems -

specimen surface not on rotation axis number of particles too small strong tendency for preferred orientation scattering from glass

Common prep techniques - powders

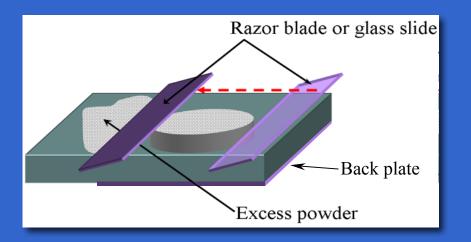
Cavity front fill

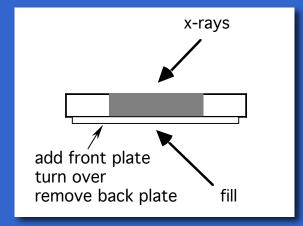


Problems tendency for preferred orientation scattering from specimen holder at low 20 angles

Common prep techniques - powders

Cavity back fill

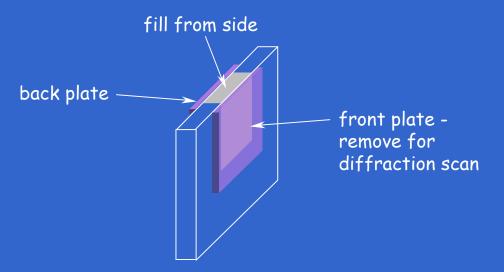




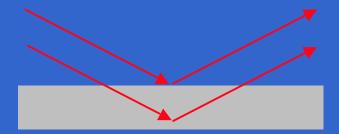
Problems slight tendency for preferred orientation scattering from specimen holder at low 20 angles

Common prep techniques - powders

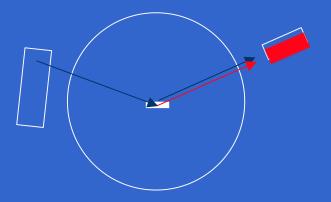
Side drift



Problem tedious sample prep Quality of powder diffraction data Is the specimen properly prepared? Note on specimens with low mass absorption coefficients sample surface must be on diffractometer rotation axis

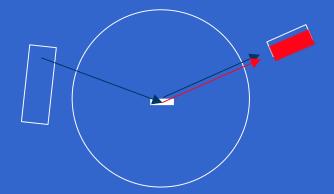


Because of low absorption, reflection comes from deep within specimen



Solution: make specimen very thin

Quality of powder diffraction data Is the specimen properly prepared? Note on specimens with low mass absorption coefficients sample surface must be on diffractometer rotation axis



Solution: make specimen very thin

Problems:

number of particles small - low intensities & non-random

scattering from specimen holder

Quality of powder diffraction data Is the specimen properly prepared? Note on specimens with low mass absorption coefficients

Problem:

scattering from specimen holder



Use single crystal with surface ground 'off-reflection' -'zero background plate' - quartz or silicon

Get from The Gem Dugout, State College PA (USA) http://www.thegemdugout.com/

For extensive survey of specimen prep techniques, see

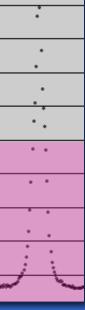
Preparation of Specimens of Specimens for X-ray Fluorescence and X-ray Diffraction Analysis, V. E. Buhrke, R. Jenkins, and D. K. Smith, eds., Wiley-VCH (February 1998)

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Need to choose:

X-radiation -	probably CuK α - changing tube	
scan range	_ variesiwithdrefasonsofiorter	
slit sizes 🔶 🛁	comparing by repeatedly	
step size	scan done by repeatedly	
step dwell time	_stepping.goramanglegtheres	
	counting atrebate applecision	

need 10120=couldted points across top of peak



Addendum - quote from Jenkins & Snyder, Introduction to X-ray Powder Diffractometry

"While the automated system (X-ray diffractometer) clearly offers many advantages (over older, manual systems), it is also clear that the automation tends to divorce the user from the actual processes involved in collection and analysis of data. Unless the user is prepared to make a conscious and often time-consuming effort to understand the procedures being employed, he or she can be easily misled by such misconceptions."